Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/634,229	BANSAL, JAI P.
Examiner	Art Unit
Sun J. Lin	2825

	SEAR	CHED	
Class	Subclass	Date	Examiner
716	1	3/21/2005	JSL
716	7	3/21/2005	JSL
716	8	3/21/2005	JSL
716	9	3/21/2005	JSL
716	16	3/29/2005	JSL
	i		1

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
716	16	3/29/2005	JSL		
716	7,9	3/21/2005	JSL		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST [USPAT;US- PGPUB;UPO;JPO;DERWENT;IBM_T DB]	3/21/2005	JSL		
EAST [USPAT;US- PGPUB;UPO;JPO;DERWENT;IBM_T DB]	3/23/2005	JSL		
EAST [USPAT;US- PGPUB;UPO;JPO;DERWENT;IBM_T DB]	3/29/2005	JSL		
IEEE	3/21/2005	JSL		
GOOGLE	3/21/2005	JSL		